

บรรณานุกรม

- [1] R.Nagarajan "Survey of Cleaning and Cleanliness Measurement in Disk Drive Manufacture" Precision Cleaning, pp. 13-22, Feb 1997.
- [2] U.Patakham "Materials Characterization with Scanning Electron Microscopy and X-Ray Microanalysis Technique" MTEC a member of NSTDA, 20, July 2006
- [3] Chris Wym "*An Introduction to BRDF-Based Lighting*" NVIDIA Corporation.
- [4] Thomas A. Germer "Modeled Integrated Scatter Tool (MIST)", Available free of charge from NIST, (2006).
- [5] Renliang Xu "Particle Characterization Light Scattering Methods" in KLUWER ACADEMIC PUBLISHERS, (2002).
- [6] Y.Mori, H.An, K.Endo, K.Yamauchi and T.Ied "A New Apparatus for Measuring Particle Sizes of the Order of Nanometer", J.JSPE Sept 1991.
- [7] S.SASAKI, H.AN, Y.MORI, T.KATAOKA, K.ENDO "Evaluation of Particle on a Si Wafer before and after Cleaning Using a New Laser Particle Counter" IEEE, 317-320, 26-28 Sept.
- [8] Thomas A. Germer "Multidetector hemispherical polarized optical scattering instrument", Published in "scattering and Surface Roughness III", Z.-H. Gu and A. A. Maradudin, Editors, Proc. SPIE 3784, 304-313 (1999)
- [9] A.R. Jones "Light scattering for particle characterization", Progress in Energy and Combustion Science (1999).
- [10] David W. Hahn "Light Scattering Theory", Department of Mechanical and Aerospace Engineering (2008).
- [11] Paul A. Webb "A primer on particle sizing by static laser light scattering", Micromeritics technical workshop series (2000).
- [12] ดุสิต เครื่องาม, 2542, สิ่งประดิษฐ์ออกแบบไดอิเล็กทริกทอริกซ์ พลาสติก เทคโนโลยีและการทำงาน เล่ม1, จุฬาลงกรณ์มหาวิทยาลัย, หน้า 339-360.
- [13] M. Born and E. Wolf "Principles of Optics", Pergamon press, Great Britain, (1980) 633 – 656

- [14] [Http://ceos.cnes.fr.8100/cdrom/ceos1/science/dg/dg15.htm](http://ceos.cnes.fr.8100/cdrom/ceos1/science/dg/dg15.htm)
- [15] NIST “National Institute of Standards and Technology” (Calibration Report #5524),
NIST Standard Reference Materials 1690, 1692, 1960, and 1961, Certification
Date: March 10, 2005
- [16] ดุสิต เครื่องงาม, 2542, สิ่งประดิษฐ์ออปโตอิเล็กทรอนิกส์ ฟิสิกส์ เทคโนโลยีและการทำงาน
เล่ม 2, จุฬาลงกรณ์มหาวิทยาลัย, หน้า 35-102.
- [17] พิเชษฐ ลิ้มสุวรรณ, 2544, เลเซอร์เทคโนโลยี, องค์การค้ำของครูสภา, หน้า 43-51.
- [18] Gasvik, K., 1995, OPTICAL METROLOGY, 2nd ed., John Wiley & Sons.
pp. 81-106.
- [19] <http://hyperphysics.phyastr.gsu.edu/Hbase/atmos/blusky.html>
- [20] 2006 APEC Nanoscale Measurement Technology Forum, Taipei, Taiwan,
September 27, 2006